

500V N-Channel Enhancement Mode MOSFET

Description

The AP5N50CD is silicon N-channel Enhanced VDMOSFETs, is obtained by the self-aligned planar Technology which reduce the conduction loss, improve switching performance and enhance the avalanche energy. The transistor can be used in various power switching circuit for system miniaturization and higher efficiency.

General Features

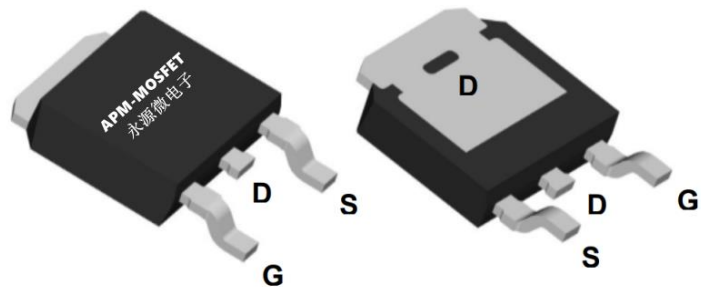
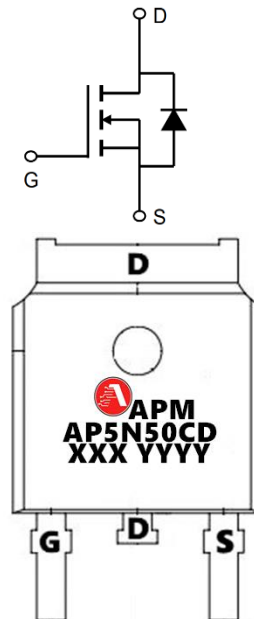
$V_{DS} = 500V$ $I_D = 4.8A$

$R_{DS(ON)} < 3.2\Omega$ @ $V_{GS}=10V$ (Type: 2.6 Ω)

Application

Uninterruptible Power Supply(UPS)

Power Factor Correction (PFC)



Package Marking and Ordering Information

Product ID	Pack	Marking	Qty(PCS)
AP5N50CD	TO-252-3L	AP5N50CD XXX YYYY	2500

Absolute Maximum Ratings ($T_c=25^{\circ}C$ unless otherwise noted)

Symbol	Parameter	Value	Unit
V_{DSS}	Drain-Source Voltage ($V_{GS} = 0V$)	500	V
I_D	Continuous Drain Current	4.8	A
I_{DM}	Pulsed Drain Current (note1)	15	A
V_{GS}	Gate-Source Voltage	± 30	V
E_{AS}	Single Pulse Avalanche Energy (note2)	57	mJ
I_{AR}	Avalanche Current (note1)	2.4	A
E_{AR}	Repetitive Avalanche Energy (note1)	6.4	mJ
P_D	Power Dissipation ($T_C = 25^{\circ}C$)	32.9	W
T_J, T_{stg}	Operating Junction and Storage Temperature Range	$-55 \sim +150$	$^{\circ}C$
R_{thJC}	Thermal Resistance, Junction-to-Case	6.25	$^{\circ}C/W$
R_{thJA}	Thermal Resistance, Junction-to-Ambient	62.5	$^{\circ}C/W$

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Electrical Characteristics ($T_J=25^{\circ}\text{C}$, unless otherwise noted)

Symbol	Parameter	Test Conditions	Min	Typ	Max	Unit
$V_{(BR)DSS}$	Drain-Source Breakdown Voltage	$V_{GS} = 0V, I_D = 250\mu A$	500	550	--	V
I_{DSS}	Zero Gate Voltage Drain Current	$V_{DS} = 650V, V_{GS} = 0V, T_J = 25^{\circ}\text{C}$	--	--	1	μA
I_{GSS}	Gate-Source Leakage	$V_{GS} = \pm 30V$	--	--	± 100	nA
$V_{GS(th)}$	Gate-Source Threshold Voltage	$V_{DS} = V_{GS}, I_D = 250\mu A$	2.0	3.0	4.0	V
$R_{DS(on)}$	Drain-Source On-Resistance (Note3)	$V_{GS} = 10V, I_D = 2.0A$	--	2.6	3.2	Ω
C_{iss}	Input Capacitance	$V_{GS} = 0V, V_{DS} = 25V, f = 1.0\text{MHz}$	--	310	--	pF
C_{oss}	Output Capacitance		--	39	--	
C_{rss}	Reverse Transfer Capacitance		--	6	--	
Q_g	Total Gate Charge	$V_{DD} = 400V, I_D = 3A, V_{GS} = 10V$	--	8	--	nC
Q_{gs}	Gate-Source Charge		--	1.2	--	
Q_{gd}	Gate-Drain Charge		--	5	--	
$t_{d(on)}$	Turn-on Delay Time	$V_{DD} = 250V, I_D = 3A, R_G = 25\Omega$	--	7.8	--	ns
t_r	Turn-on Rise Time		--	33	--	
$t_{d(off)}$	Turn-off Delay Time		--	23	--	
t_f	Turn-off Fall Time		--	59	--	
I_S	Continuous Body Diode Current	$T_C = 25^{\circ}\text{C}$	--	--	3.0	A
I_{SM}	Pulsed Diode Forward Current		--	--	12	A
V_{SD}	Body Diode Voltage	$T_J = 25^{\circ}\text{C}, I_{SD} = 3A, V_{GS} = 0V$	--	--	1.4	V
t_{rr}	Reverse Recovery Time	$V_{GS} = 0V, I_S = 3A, di_F/dt = 100A/\mu s$	--	80	--	ns
Q_{rr}	Reverse Recovery Charge		--	1.8	--	μC

Note :

- 1、The data tested by surface mounted on a 1 inch² FR-4 board with 2OZ copper.
- 2、The EAS data shows Max. rating . $I_{AS} = 2.4A, V_{DD} = 50V, R_G = 25\Omega$, Starting $T_J = 25^{\circ}\text{C}$
- 3、The test condition is Pulse Test: Pulse width $\leq 300\mu s$, Duty Cycle $\leq 1\%$
- 4、The power dissipation is limited by 150°C junction temperature
- 5、The data is theoretically the same as I_D and I_{DM} , in real applications , should be limited by total power dissipation.

Typical Characteristics

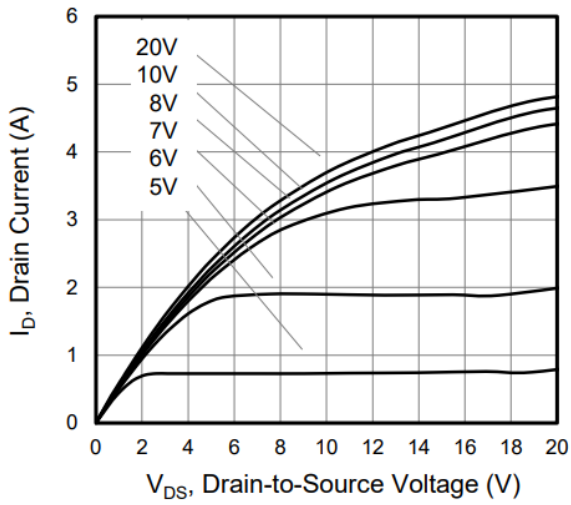


Figure 1. Output Characteristics (T_J = 25°C)

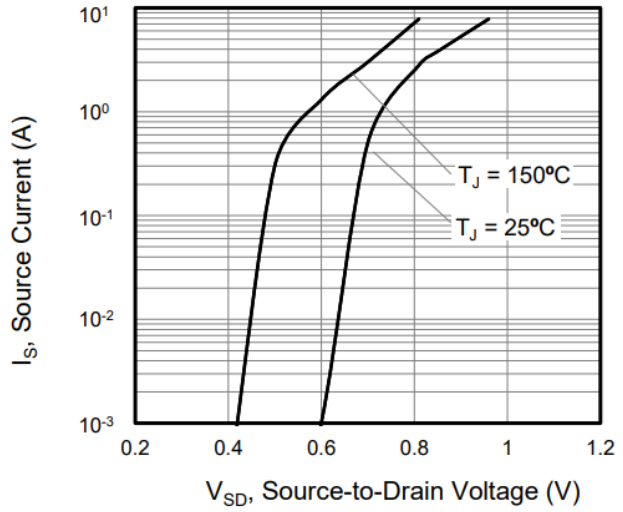


Figure 2. Body Diode Forward Voltage

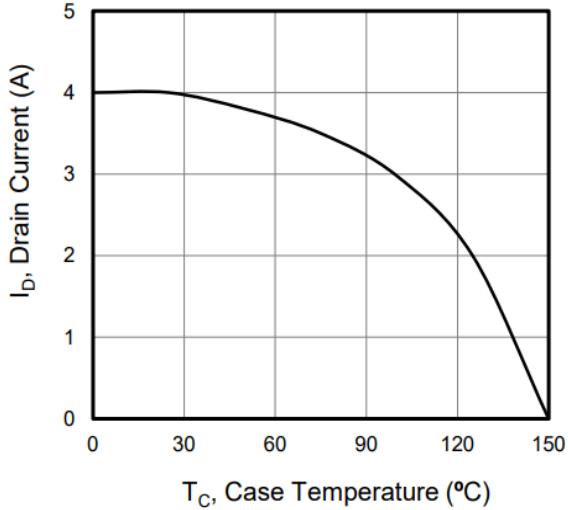


Figure 3. Drain Current vs. Temperature

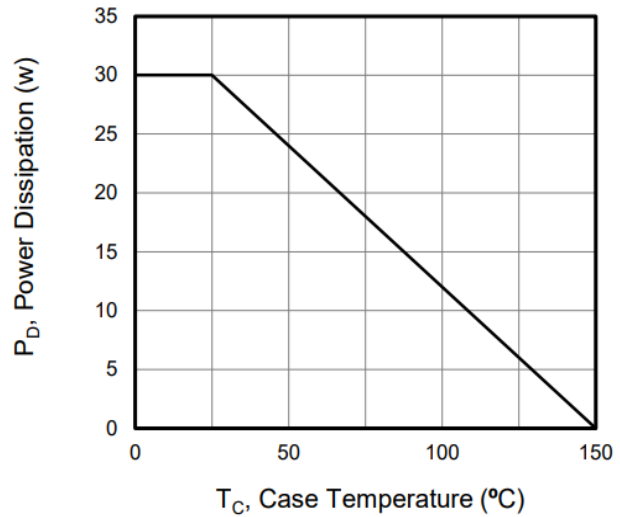


Figure 4. BV DSS Variation vs. Temperature

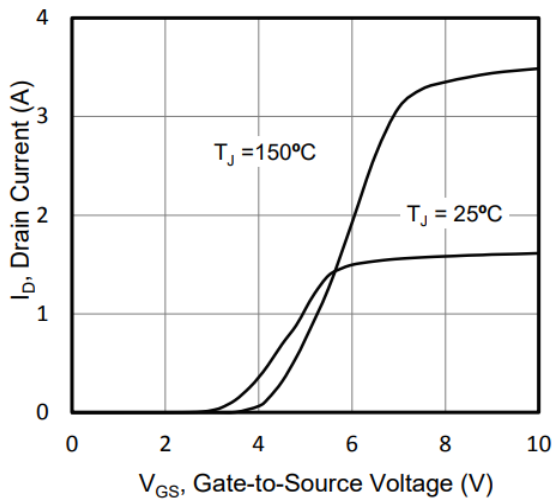


Figure 5. Transfer Characteristics

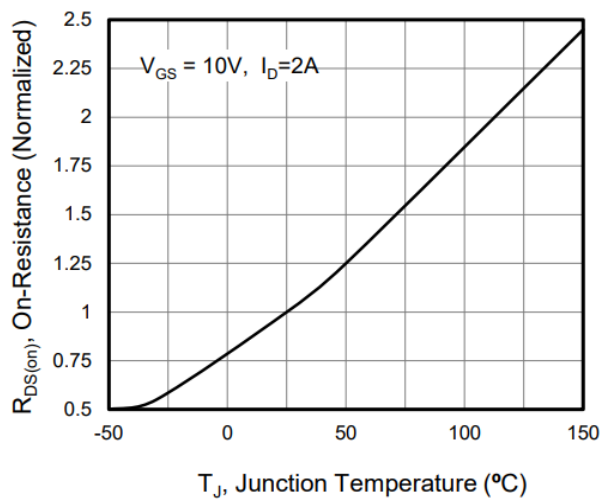


Figure 6. On-Resistance vs. Temperature

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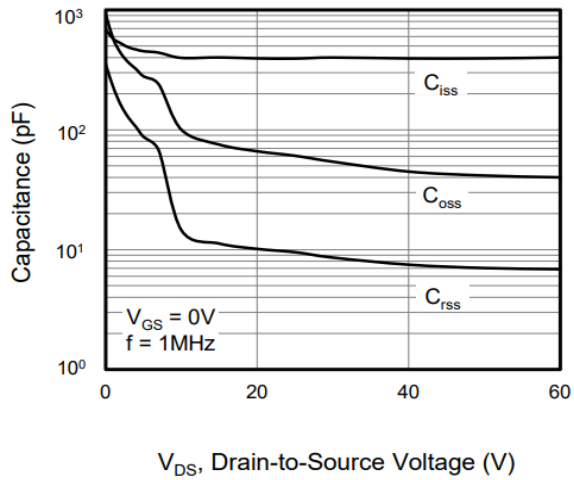


Figure 7. Capacitance

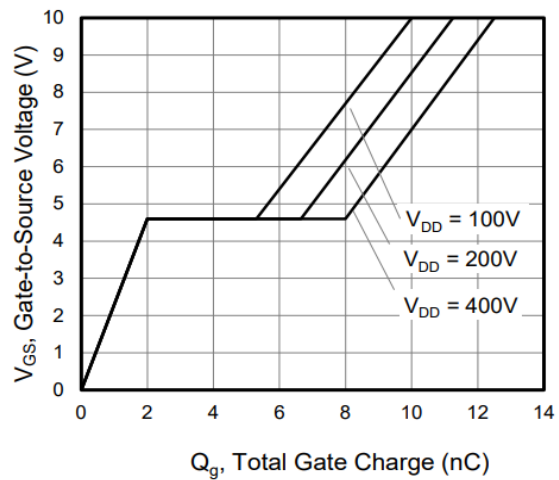


Figure 8. Gate Charge

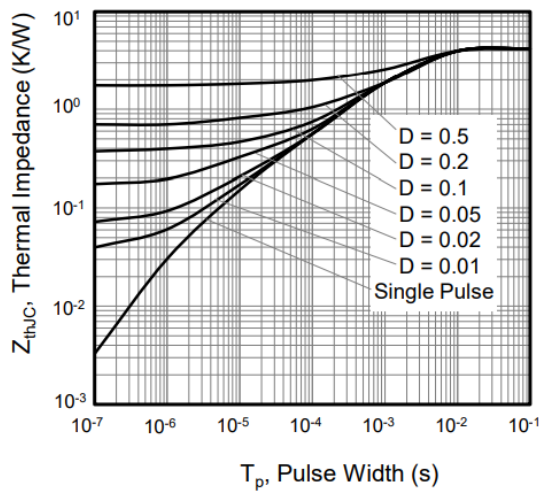
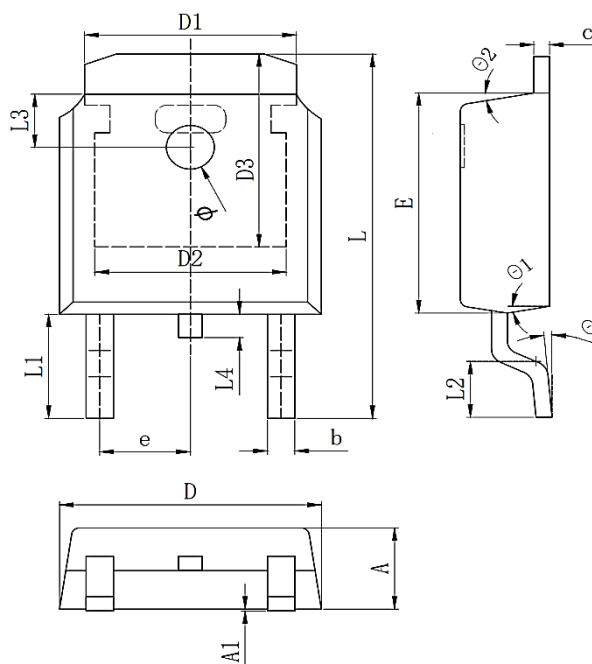


Figure 9. Transient Thermal Impedance

Package Mechanical Data-TO-252-3L



Symbol	Dim in mm		
	Min	Typ	Max
A	2.1	2.3	2.5
A1	0	0.064	0.128
b	0.64	0.75	0.86
c	0.45	0.52	0.6
D	6.4	6.6	6.8
D1	5.33REF		
D2	4.83REF		
D3	5.25REF		
E	5.9	6.1	6.3
e	2.286TYP		
L	9.8	10.1	10.4
L1	2.888REF		
L2	1.4	1.5	1.7
L3	1.65REF		
L4	0.6	0.8	1
φ	1.1	1.2	1.3
θ	0°		10°
θ1	5°		10°
θ2	5°		10°

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Edition	Date	Change
REV1.0	2023/4/31	Initial release

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